
Latent Damage and Reliability in Semiconductor Devices

Advisor: Dr. Randall Geiger**Client:** Dr. Randall Geiger, EcpE**Members (roles):**

Sean Santella (Leader)

Jaehyuk Han (Webmaster)

Hayle Olson (Communication Leader)

David Ackerman (Key Concept Holder)

Weekly Summary:

This week we met with our advisor and discussed our test procedure. We now know specific details of what we need to include and how we need to test our devices. We also looked into how we need to go about purchasing an electric fencer.

Meeting Notes:Advisor/Client Meeting (Oct. 14th at 9AM)*Duration:* 1 Hour*Members Present:* Dr. Geiger, Sean Santella, Jaehyuk Han, David Ackerman*Notes:* This meeting was held with Dr. Geiger to discuss our test procedure, specifically the ESD stress and burn-in testing. We clarified that we need to stress all the input pins on the device while the outputs are tied low. Dr. Geiger also requested that we purchase an electric fencer this week.**Weekly Accomplishments:**

We developed a better understanding of how to perform our experiment/research. We also researched a suitable electric fencer (high voltage source).

Plans for Next Week:

- Continue developing a more in-depth experiment to perform
 - Look over schematics and details of the burn-in boards that are being provided
- Finish up our design document
- Purchase an electric fencer

Pending Issues:

We currently do not have any pending issues.

Individual Contributions:

Sean Santella: Attended lecture and weekly advisor meeting, researched electric fencer (high voltage source).

Jaehyuk Han: Attended lecture and weekly advisor, researched the provided PCB design papers.

Hayle Olson: Attended lecture and wrote weekly report.

David Ackerman: Attended lecture and weekly advisor meeting, researched the provided PCB design papers.

Hourly Contributions:

<u>Member:</u>	<u>Weekly Hours:</u>	<u>Total Hours:</u>
Sean Santella	2.5	22.5
Jaehyuk Han	3.0	20.0
Hayle Olson	1.5	20.0
David Ackerman	2.5	21.0